

## AMENDMENTS

### *In the Specification*

Please amend the specification on Page 4, Lines 13 through 23 as follows:

The performance monitor circuit 112 provides the capability of collecting probe data signals and associating a temporal identifier, such as a time stamp, to the probe data signals. In an embodiment of the present technology, the performance monitoring circuit 112 ~~chip 138~~ can be the MultiKron chip provided by the National Institute of Standards and Technology (NIST). However, it should be noted that this invention is not limited to this particular performance monitoring chip and that others can be used. A more detailed description of the MultiKron performance monitoring chip is found in Mink, et al., "MultiKron: Performance Measurement Instrumentation," Proc. IEEE International Computer Performance and Dependability Symposium, Urbana-Champaign, Illinois, (September 1996), which is hereby incorporated by reference as background information.